



Features

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology
- ★ 100% EAS Guaranteed

Description

THE 4606A is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

THE 4606A meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

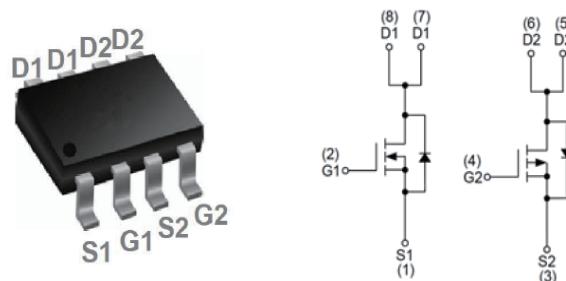
Product Summary

BVDSS	RDS(on)	ID
30V	18mΩ	7A
-30V	35mΩ	-6A

Applications

- ★ Power management in half bridge and inverters
- ★ DC-DC Converter
- ★ Load Switch

SOP8 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-Channel	P-Channel	
V _{DS}	Drain-Source Voltage	30	-30	V
V _{GS}	Gate-Source Voltage	±20	±20	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	7	-6	A
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	6	-4	
I _{DM}	Pulsed Drain Current ²	20	-12	A
E _{AS}	Single Pulse Avalanche Energy ³	72	59	
I _{AS}	Avalanche Current	21	-19	A
P _D @T _C =25°C	Total Power Dissipation ⁴	2.5	2.08	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	-55 to 150	

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ¹	-	85	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	-	50	°C/W

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_D=250\mu\text{A}$	30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	BVDSS Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	-	0.034	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}, I_D=6\text{A}$	-	18	25	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_D=5\text{A}$	-	25	31	
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}, I_D=250\mu\text{A}$	1	1.5	2.5	V
$\Delta V_{\text{GS}(\text{th})}$	$V_{\text{GS}(\text{th})}$ Temperature Coefficient		-	-5.8	-	$\text{mV}/^\circ\text{C}$
I_{DS}	Drain-Source Leakage Current	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, T_J=25^\circ\text{C}$	-	-	1	uA
		$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, T_J=55^\circ\text{C}$	-	-	5	
I_{GS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
g_{fs}	Forward Transconductance	$V_{\text{DS}}=15\text{V}, I_D=5\text{A}$	-	10	-	S
R_g	Gate Resistance	$V_{\text{DS}}=24\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	2.5	-	Ω
Q_g	Total Gate Charge (4.5V)	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=4.5\text{V}, I_D=6\text{A}$	-	7.2	-	nC
Q_{gs}	Gate-Source Charge		-	1.4	-	
Q_{gd}	Gate-Drain Charge		-	2.2	-	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=12\text{V}, V_{\text{GS}}=10\text{V}, R_G=3.3\Omega, I_D=5\text{A}$	-	3.9	-	ns
T_r	Rise Time		-	9.2	-	
$T_{\text{d(off)}}$	Turn-Off Delay Time		-	14.5	-	
T_f	Fall Time		-	6	-	
C_{iss}	Input Capacitance	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	370	-	pF
C_{oss}	Output Capacitance		-	54	-	
C_{rss}	Reverse Transfer Capacitance		-	40	-	

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	$V_{\text{DD}}=25\text{V}, L=0.1\text{mH}, I_{\text{AS}}=10\text{A}$	16	--	--	mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,6}	$V_G=V_D=0\text{V}$, Force Current	--	--	7	A
I_{SM}	Pulsed Source Current ^{2,6}		--	--	20	A
V_{SD}	Diode Forward Voltage ²	$V_{\text{GS}}=0\text{V}, I_s=5\text{A}, T_J=25^\circ\text{C}$	--	--	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=25\text{V}, V_{\text{GS}}=10\text{V}, L=0.1\text{mH}, I_{\text{AS}}=10\text{A}$.
- 4.The power dissipation is limited by 150°C junction temperature .
- 5.The Min. value is 100% EAS tested guarantee.
- 6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -30V, V_{GS} = 0V$	-	-	-1	μA
I_{GSS}	Gate-Source Leakage	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
$V_{GS(\text{th})}$	Gate-Source Threshold voltage	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1	-1.5	-2.5	V
$R_{DS(on)}$	Drain-Source on-State Resistance ³	$V_{GS} = -10V, I_D = -4.1A$	-	36	60	$\text{m}\Omega$
		$V_{GS} = -4.5V, I_D = -3A$	-	50	85	
Dynamic Characteristics ⁴						
C_{iss}	Input Capacitance	$V_{GS} = 0V, V_{DS} = -15V, f = 1.0\text{MHz}$	-	530	-	pF
C_{oss}	Output Capacitance		-	70	-	
C_{rss}	Reverse Transfer Capacitance		-	56	-	
Switching Characteristics ⁴						
Q_g	Total Gate Charge	$V_{GS} = -10V, V_{DS} = -15V, I_D = -4.1A$	-	6.8	-	nC
Q_{gs}	Gate-Source Charge		-	1	-	
Q_{gd}	Gate-Drain Charge		-	1.4	-	
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = -10V, V_{DS} = -15V, R_L = 15\Omega, R_{GEN} = 2.5\Omega$	-	14	-	ns
t_r	Rise Time		-	61	-	
$t_{d(off)}$	Turn-off Delay time		-	19	-	
t_f	Fall Time		-	10	-	
Source-Drain Body Diode Characteristics						
V_{SD}	Diode Forward Voltage ³	$I_S = -4.1A, V_{GS} = 0V$	-	-	-1.2	V
I_S	Continuous Source Current		-	-	-56	A

Notes:

- Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.
- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
- Pulse Test: Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- This value is guaranteed by design hence it is not included in the production test.

N-Channel Typical Performance Characteristics

Figure 1: Typical Output Characteristics

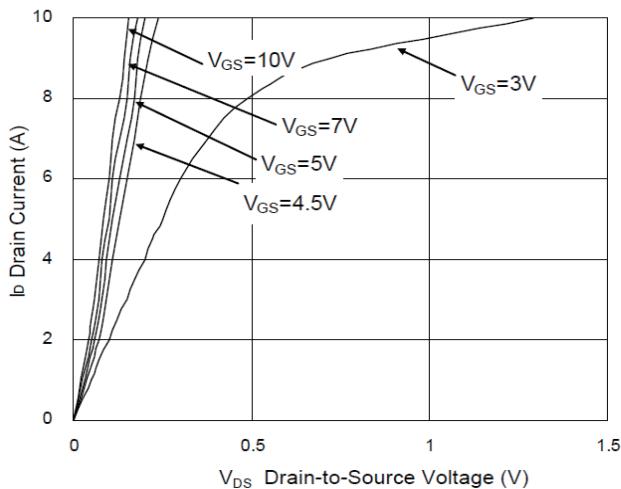


Figure 2: On-Resistance vs. G-S Voltage

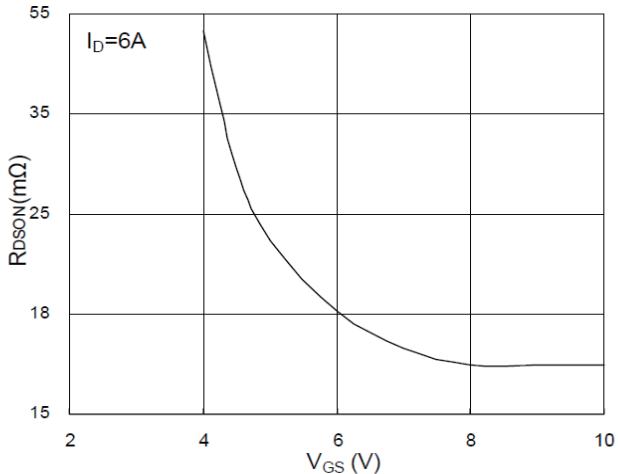


Figure 3: Forward Characteristics of Reverse Current

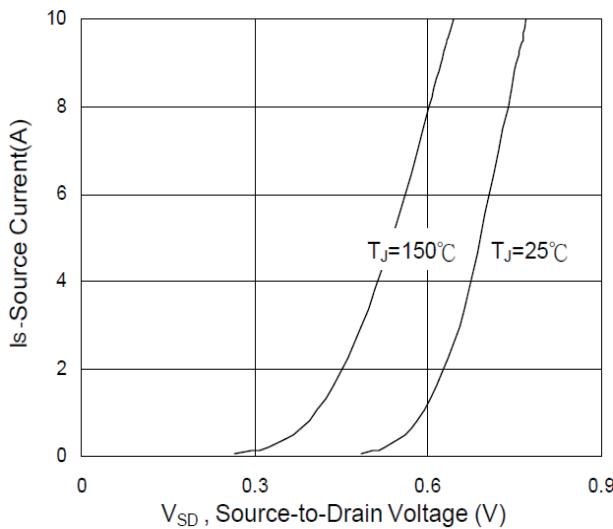


Figure 4: Gate-charge Characteristics

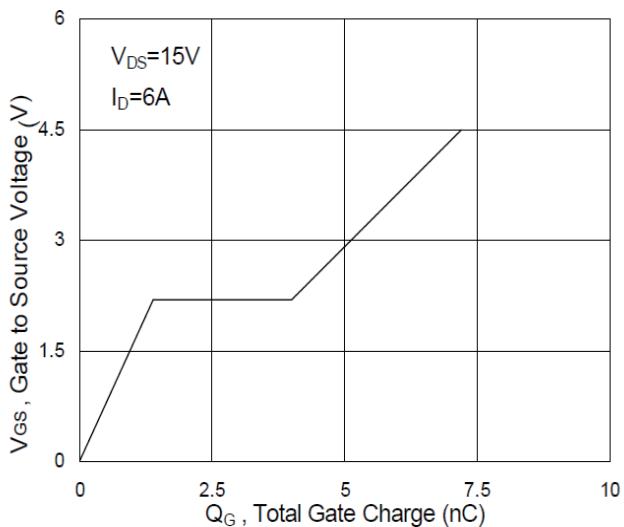
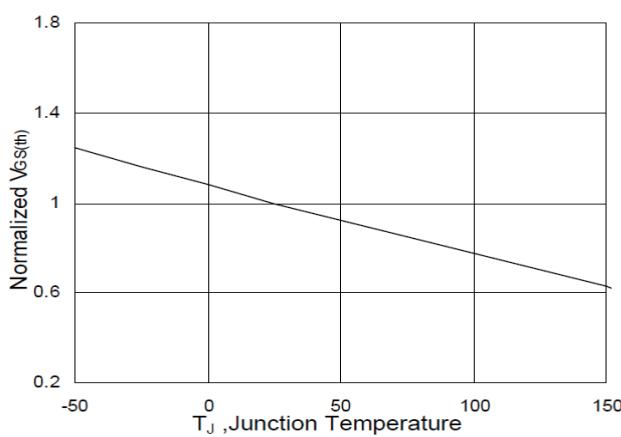
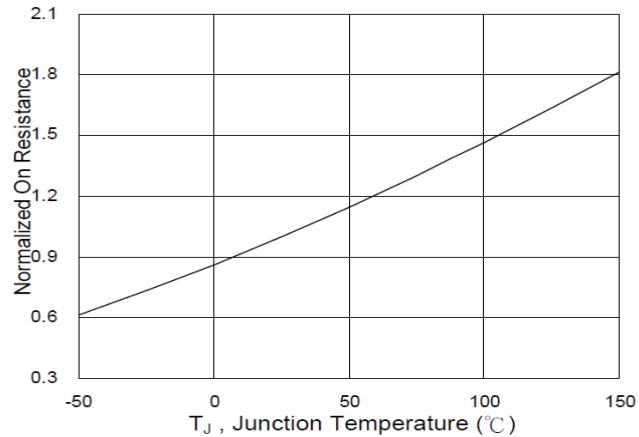
Figure 5: $V_{GS(th)}$ vs. T_J 

Figure 6: Normalized RDSON vs. TJ





N-Channel Typical Performance Characteristics

Figure 7: Capacitance

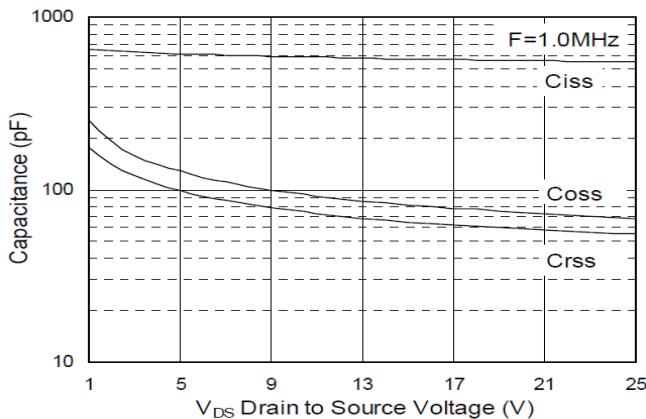


Figure 8: Safe Operating Area

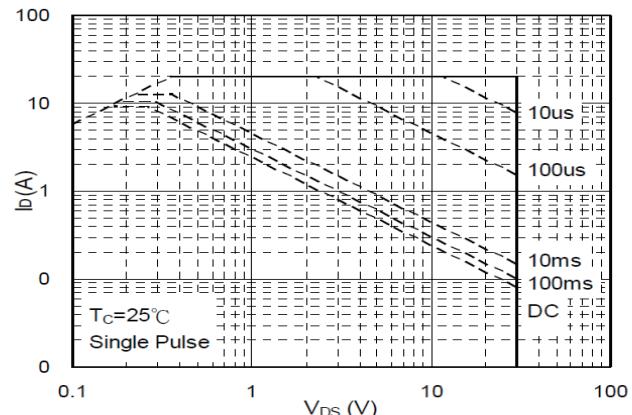


Figure 9: Normalized Maximum Transient

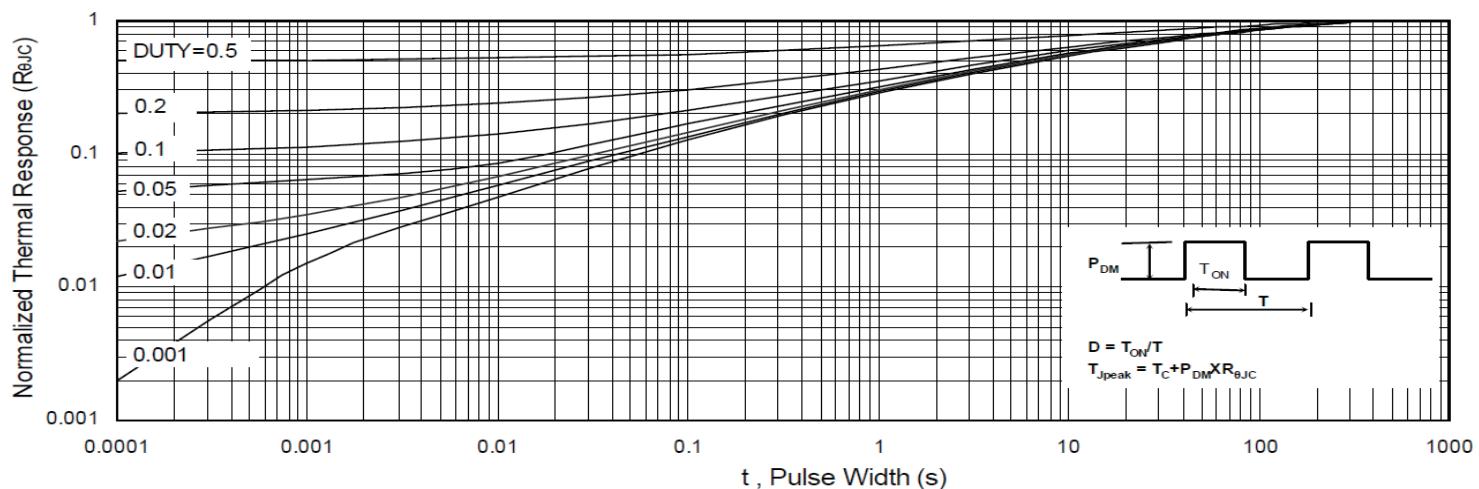


Figure 10: Switching Time Waveform

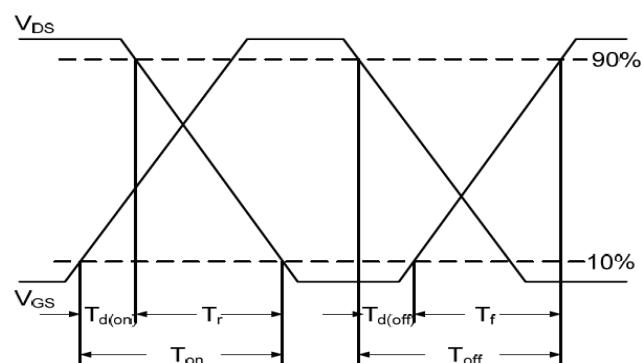
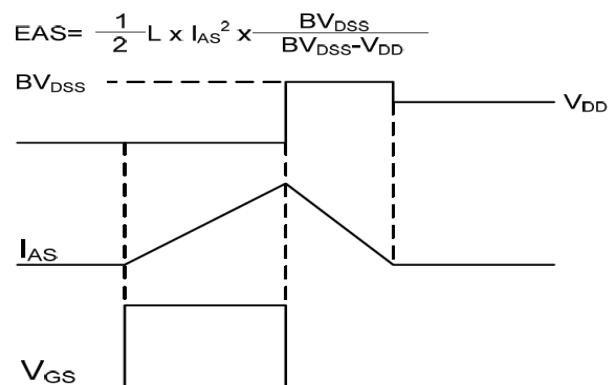


Figure 11: Unclamped Inductive Waveform



P-Channel Typical Performance Characteristics

Figure 1: Typical Output Characteristics

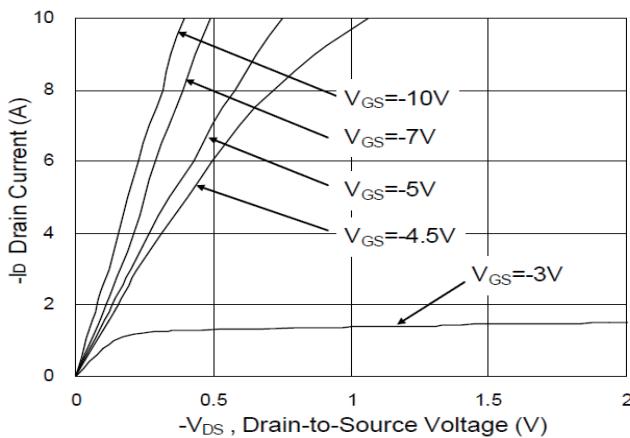


Figure 2: On-Resistance vs. G-S Voltage

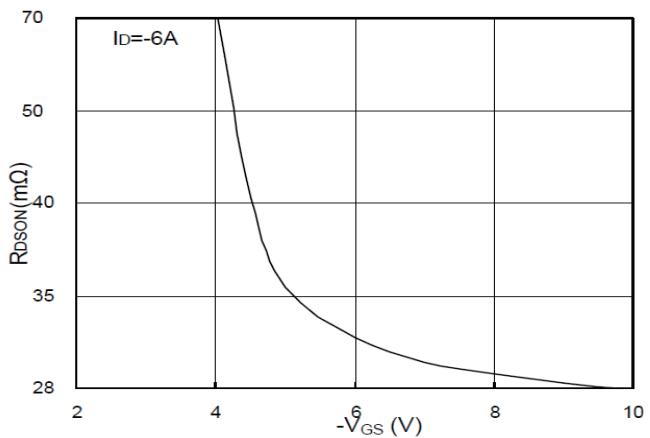


Figure 3: Forward Characteristics of Reverse Current

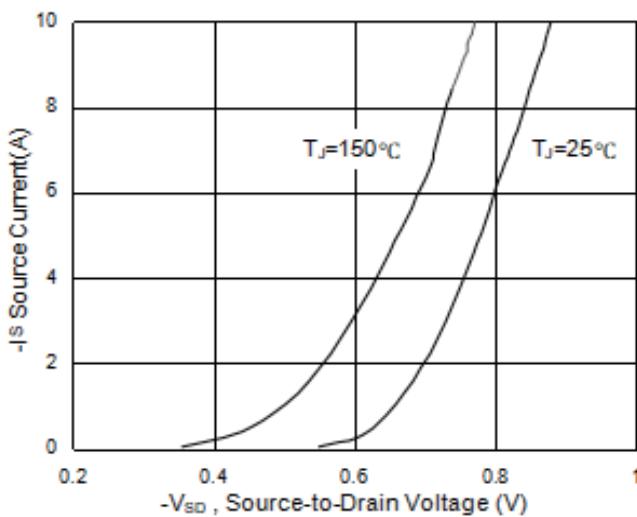


Figure 4: Gate-charge Characteristics

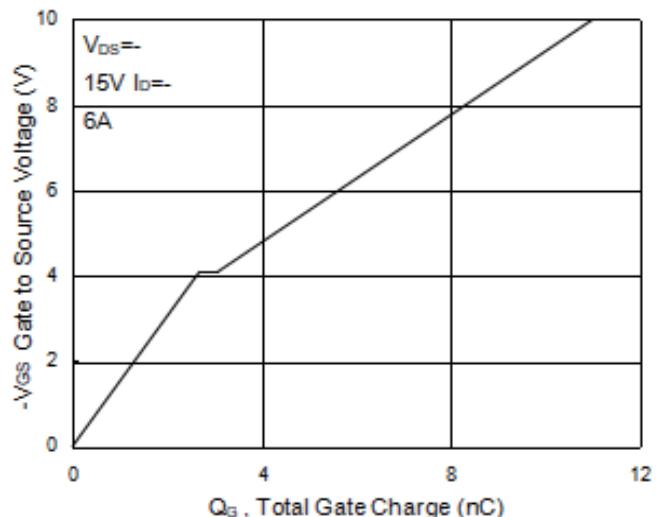


Figure 5: $V_{GS(th)}$ vs. T_J

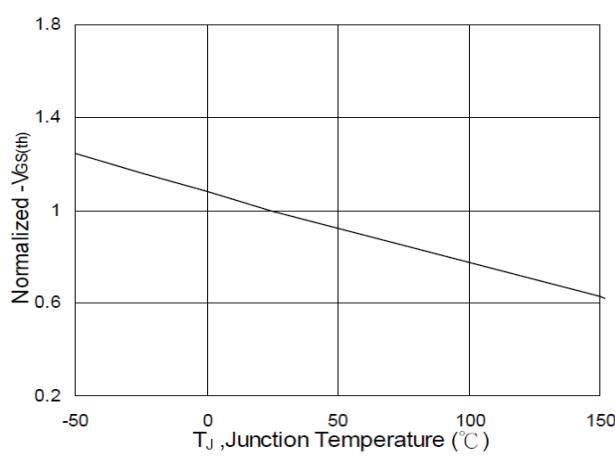
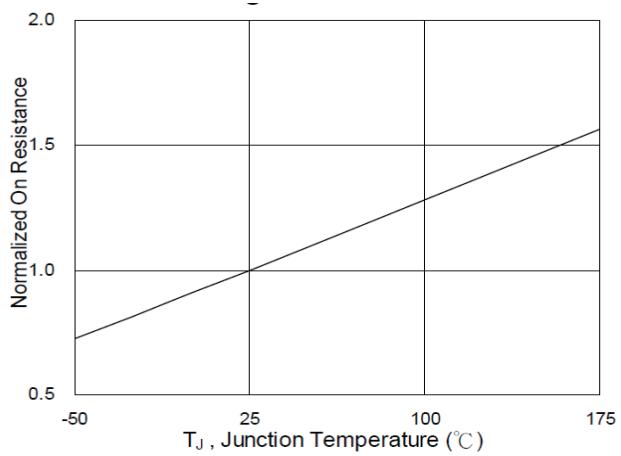


Figure 6: Normalized RDS(on) vs. T_J



P-Channel Typical Performance Characteristics

Figure7:Capacitance

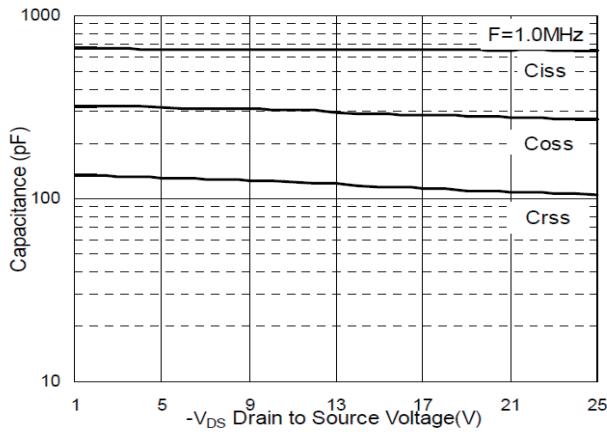


Figure 8: Safe Operating Area

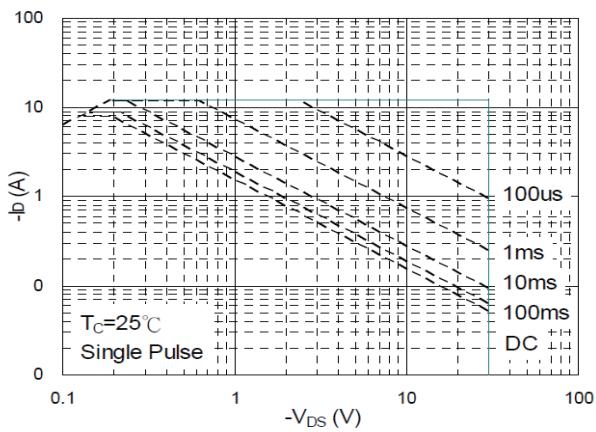


Figure9:Normalized Maximum Transient

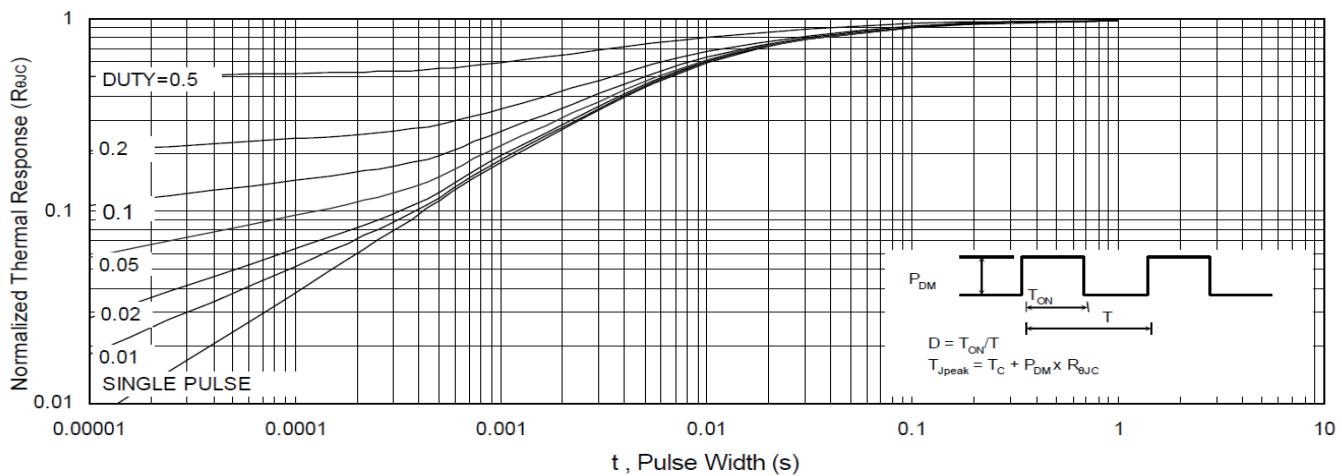


Figure10:Switching Time Waveform

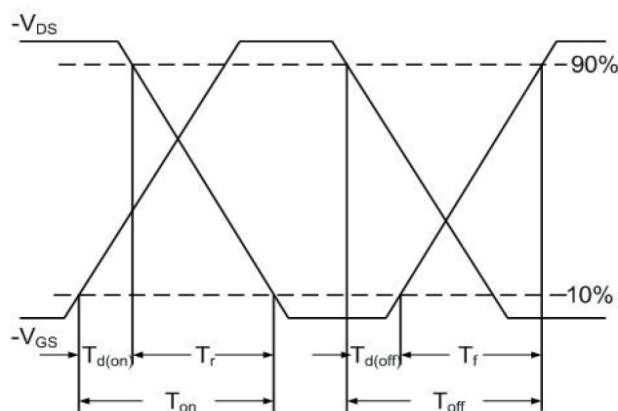


Figure 11: Unclamped Inductive Waveform

